

Notice of References Cited	Application/Control No. 10/563,641	Applicant(s)/Patent Under Reexamination VAN DER WAL ET AL.	
	Examiner Arun Williams	Art Unit 2838	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,298,838 A	11-1981	Akamatsu et al.	324/117R
*	B	US-4,811,184 A	03-1989	Koninsky et al.	363/17
*	C	US-5,602,464 A	02-1997	Linkowsky et al.	323/272
*	D	US-5,661,348 A	08-1997	Brown, Alan E.	307/43
*	E	US-6,441,597 B1	08-2002	Lethellier, Patrice R.	323/282
*	F	US-2002/0185987 A1	12-2002	Kushida et al.	318/599
*	G	US-6,501,342 B2	12-2002	Marten, Victor	331/173
*	H	US-2004/0041548 A1	03-2004	Perry, Marty	323/282
*	I	US-6,895,229 B2	05-2005	Schetelig et al.	455/226.1
*	J	US-6,944,034 B1	09-2005	Shteynberg et al.	363/21.13
*	K	US-7,092,265 B2	08-2006	Kernahan, Kent	363/65
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.